| PCN Number: | 20181127000.0 | PCN Date: | Dec. 11, 2018 |
|---|---|---|---|
| Title: | Datasheet for TUSB564,TUSB1064 | | |
| Customer Contact: | PCN Manager | Dept: | Quality Services |

**Change Type:**

| | | | | | |
|---|---|---|---|---|---|
| ☐ | Assembly Site | ☐ | Design | ☐ | Wafer Bump Site |
| ☐ | Assembly Process | ☒ | Data Sheet | ☐ | Wafer Bump Material |
| ☐ | Assembly Materials | ☐ | Part number change | ☐ | Wafer Bump Process |
| ☐ | Mechanical Specification | ☐ | Test Site | ☐ | Wafer Fab Site |
| ☐ | Packing/Shipping/Labeling | ☐ | Test Process | ☐ | Wafer Fab Materials |
| | | | | ☐ | Wafer Fab Process |

## Notification Details

**Description of Change:**

Texas Instruments Incorporated is announcing an information only notification.
The product datasheet(s) is being updated as summarized below.
The following change history provides further details.

TEXAS INSTRUMENTS

**TUSB564**

SLLSF29D – OCTOBER 2017 – REVISED NOVEMBER 2018

| Changes from Revision C (February 2018) to Revision D | Page |
|---|---|
| • Changed the RNQ pin image appearance | 3 |
| • Changed the EN pin Description in the *Pin Functions* table | 4 |
| • Changed the HPDIN pin From: I/O To: 2 Level I | 4 |
| • Added pull-down indicator (PD) in the I/O column on FLIP/SCL and CTL0/SDA pins | 4 |
| • Added Junction temperature to absolute maximum ratings table | 5 |
| • From: Internal pull-down resistance for CTL1. To: Internal pull-down resistance for CTL1, CTL0, FLIP, and EN | 6 |
| • Deleted EN from Note 1 of Table 8 | 23 |

TEXAS INSTRUMENTS

**TUSB1064**

SLLSF48A – MARCH 2018 – REVISED NOVEMBER 2018

| Changes from Original (March 2018) to Revision A | Page |
|---|---|
| • Changed the RNQ pin image appearance | 3 |
| • Changed the column on EN From: I To: 2 Level I (PD) | 4 |
| • Changed the EN pin Description in the *Pin Functions* table | 4 |
| • Changed the HPDIN pin From: I/O To: 2 Level I | 4 |
| • Added pull-down indicator (PD) in the I/O column on FLIP/SCL and CTL0/SDA pins | 4 |
| • Added Junction temperature to absolute maximum ratings table. | 5 |
| • From: Internal pull-down resistance for CTL1. To: Internal pull-down resistance for CTL1, CTL0, FLIP, and EN. | 6 |
| • Deleted EN from Note 1 of Table 8 | 23 |

The datasheet number will be changing.

| Device Family | Change From: | Change To: |
|---|---|---|
| TUSB564 | SLLSF29C | SLLSF29D |
| TUSB1064 | SLLSF48 | SLLSF48A |

These changes may be reviewed at the datasheet links provided.

http://www.ti.com/product/TUSB564

http://www.ti.com/product/TUSB1064

**Reason for Change:**

To accurately reflect device characteristics.

**Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):**

No anticipated impact. This is a specification change announcement only. There are no changes to the actual device.

| Changes to product identification resulting from this PCN: | | | |
|---|---|---|---|
| None. | | | |
| **Product Affected:** | | | |
| TUSB564IRNQR | TUSB564IRNQT | TUSB564RNQR | TUSB564RNQT |
| TUSB1064IRNQR | TUSB1064IRNQT | TUSB1064RNQR | TUSB1064RNQT |

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

| Location | E-Mail |
|---|---|
| USA | PCNAmericasContact@list.ti.com |
| Europe | PCNEuropeContact@list.ti.com |
| Asia Pacific | PCNAsiaContact@list.ti.com |
| Japan | PCNJapanContact@list.ti.com |